



# HST50N10

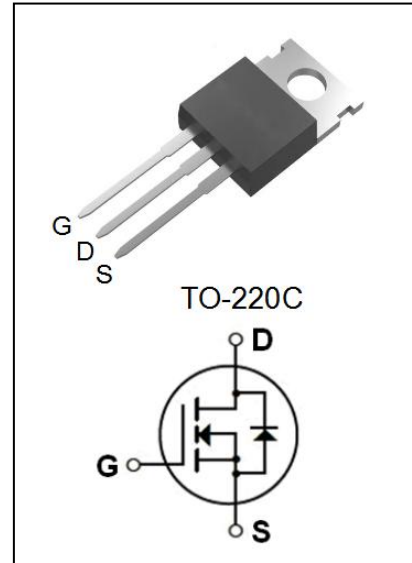
100V N-Channel MOSFET

● **Features:**

- 50A, 100V,  $R_{DS(on)(Typ)} = 13m\Omega @ V_{GS}=10V$
- Low Gate Charge
- Low  $C_{rSS}$
- 100% Avalanche Tested
- Fast Switching
- Improved dv/dt Capability

● **Application:**

- High Frequency Switching Mode Power Supply
- Active Power Factor Correction




**Absolute Maximum Ratings**( $T_c=25^\circ C$  unless otherwise noted)

Symbol	Parameter	Value	Unit
$V_{DSS}$	Drain-Source Voltage	100	V
$I_D$	Drain Current - Continuous( $T_c=25^\circ C$ ) - Continuous( $T_c=100^\circ C$ )	50*	A
		31.6*	A
$I_{DM}$	Drain Current -Pulsed	200*	A
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulsed Avalanche Energy ( Limit Reference Value ) (Note5)	74	mJ
$P_D$	Power Dissipation( $T_C =25^\circ C$ ) -Derate above $25^\circ C$	90	W
		0.72	W/ $^\circ C$
$T_j$	Operating Junction Temperature	150	$^\circ C$
$T_{stg}$	Storage Temperature Range	-55 to+150	$^\circ C$

**Thermal Characteristics**

Symbol	Parameter	Max	Unit
$R_{\theta JC}$	Thermal Resistance,Junction to Case (Note2)	1.39	$^\circ C /W$

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**Electrical Characteristics**(Tc=25°C unless otherwise noted)

Symbol	Parameter	Test Conditons	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
BV <sub>DSS</sub>	Drain-source Breakdown Voltage	V <sub>GS</sub> =0V ,I <sub>D</sub> =250μA	100	--	--	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V	--	--	1	μA
I <sub>GSSF</sub>	Gate-Body Leakage Current,Forward	V <sub>GS</sub> =+20V, V <sub>DS</sub> =0V	--	--	100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current,Reverse	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V	--	--	-100	nA
<b>On Characteristics</b> (Note3)						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA	1.2	1.7	2.5	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10 V, I <sub>D</sub> =25A	--	13	17	mΩ
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =6 V, I <sub>D</sub> =25A	--	15	20	mΩ
<b>Dynamic Characteristics</b> (Note4)						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1.0MHz	--	1280	--	pF
C <sub>oss</sub>	Output Capacitance		--	510	--	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		--	43	--	pF
<b>Switching Characteristics</b> (Note4)						
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 50 V, I <sub>D</sub> =20 A, R <sub>G</sub> =3.05 Ω, V <sub>GS</sub> =10V	--	5.6	--	ns
t <sub>r</sub>	Turn-On Rise Time		--	29	--	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		--	28	--	ns
t <sub>f</sub>	Turn-Off Fall Time		--	9.9	--	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 80 V, I <sub>D</sub> =20A, V <sub>GS</sub> = 10 V	--	24	--	nC
Q <sub>gs</sub>	Gate-Source Charge		--	5.3	--	nC
Q <sub>gd</sub>	Gate-Drain Charge		--	5.9	--	nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current (Note2)		--	--	50	A
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current		--	--	200	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =25A (Note3)	--	--	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> =0V, I <sub>S</sub> =20A, d I <sub>F</sub> /dt=100A/μs (Note3)	--	41	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge		--	42	--	nC

Notes:

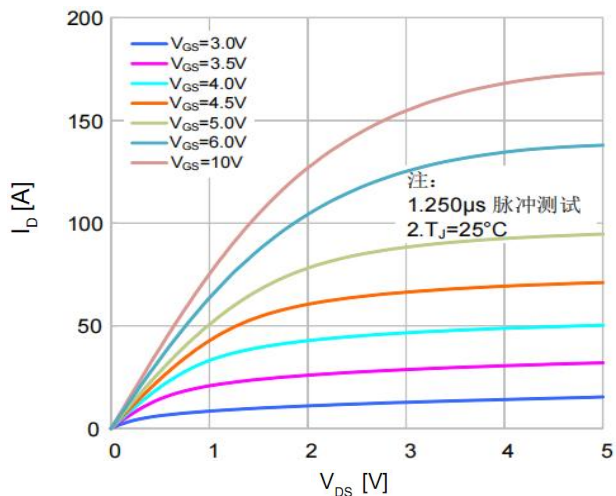
- 1、Repetitive Rating:Pulse Width Limited by Maximum Junction Temperature.
- 2、Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3、Pulse Test : Pulse Width ≤300 μ s, Duty Cycle≤2%.
- 4、Guaranteed by design, not subject to production.
- 5、EAS condition: L = 0.5mH, I<sub>AS</sub> =13A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C.



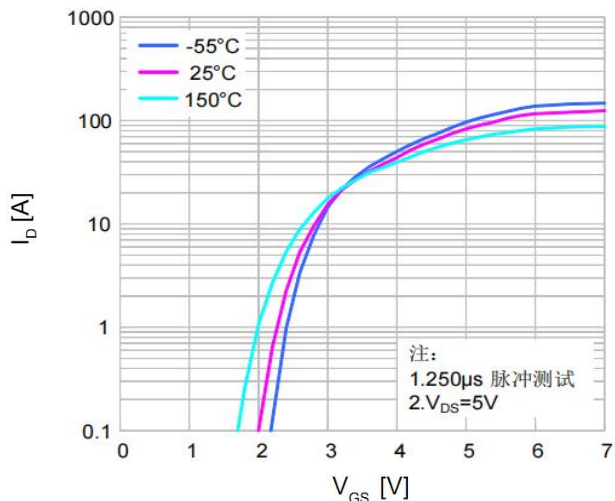
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## 100V N-Channel MOSFET

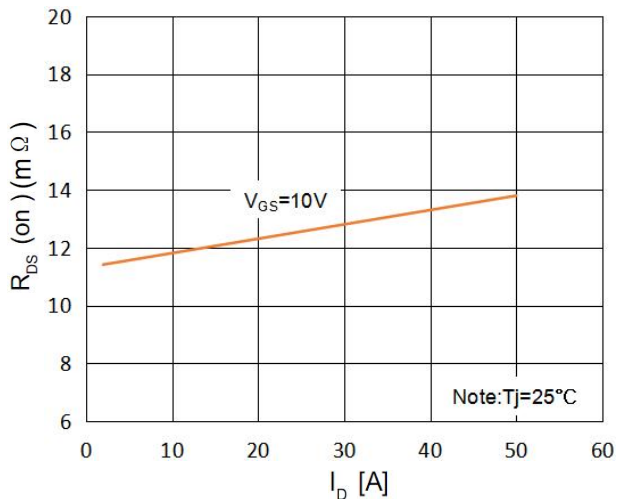
### On-Regin Characteristics



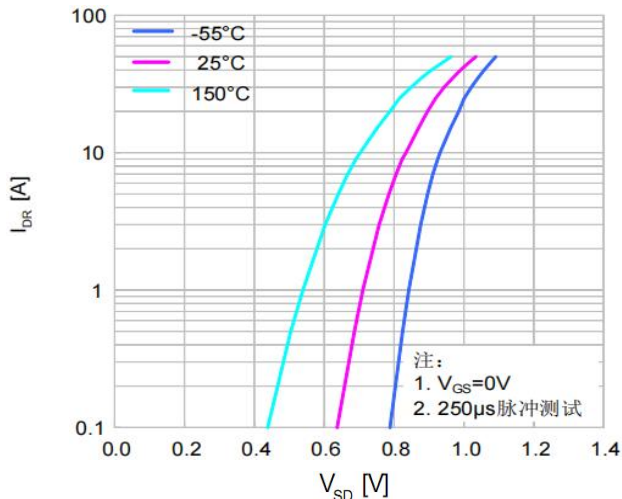
### Transfer Characteristics



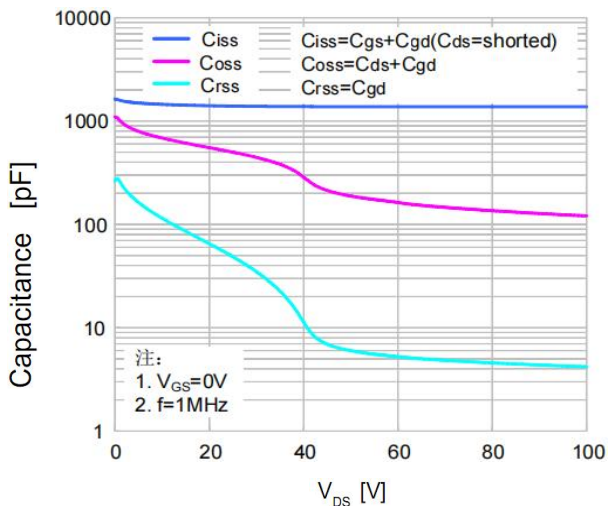
### On-Resistance Variation vs. Drain Current and Gate Voltage



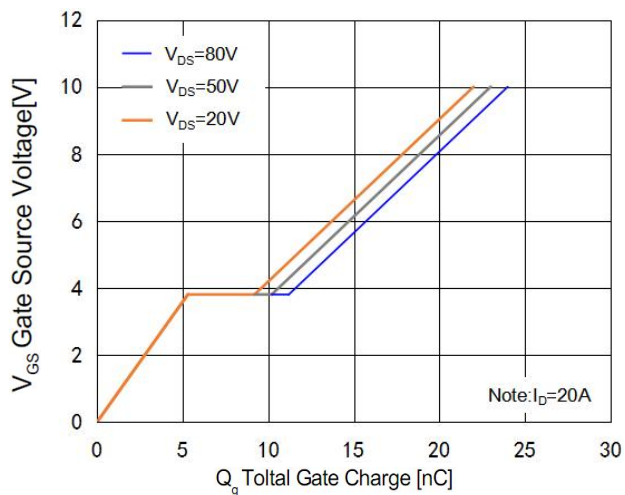
### Body Diode Forward Voltage Variation vs. Source Current and Temperature



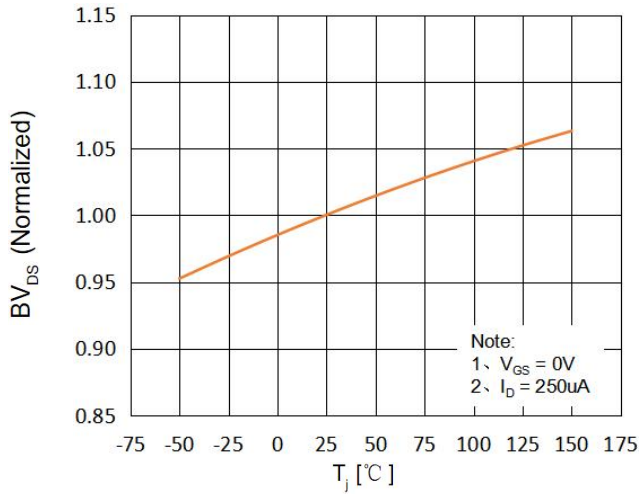
### Capacitance Characteristics



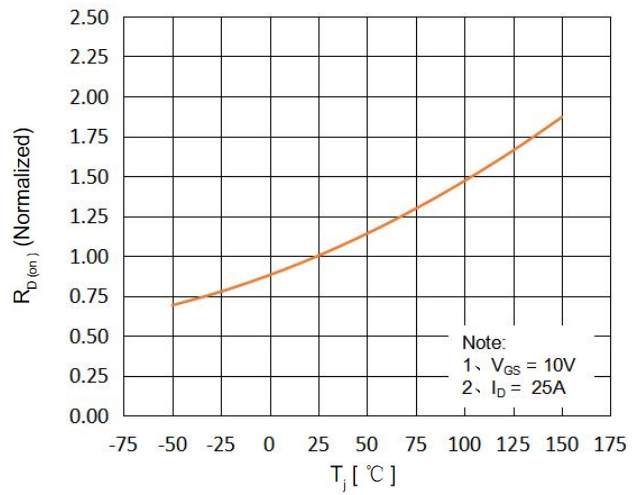
### Gate Charge Characteristics



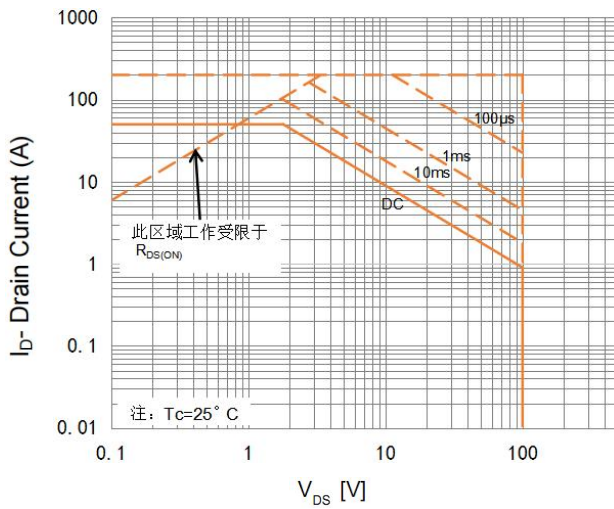
### Breakdown Voltage Variation vs. Temperature



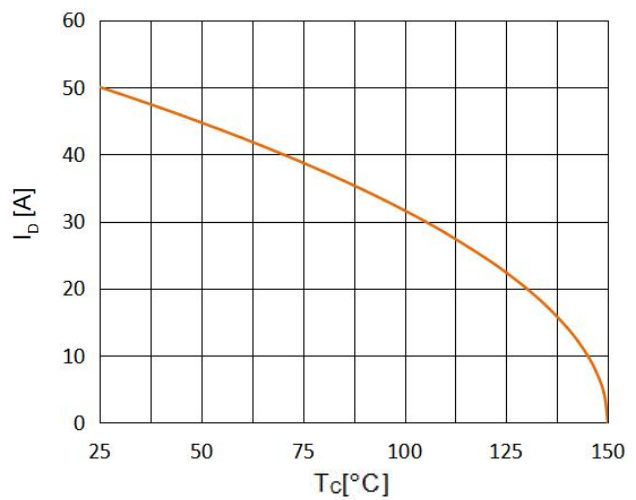
### On-Resistance Variation vs. Temperature



### Maximum Safe Operating Area



### Maximum Drain Current Vs. Case Temperature





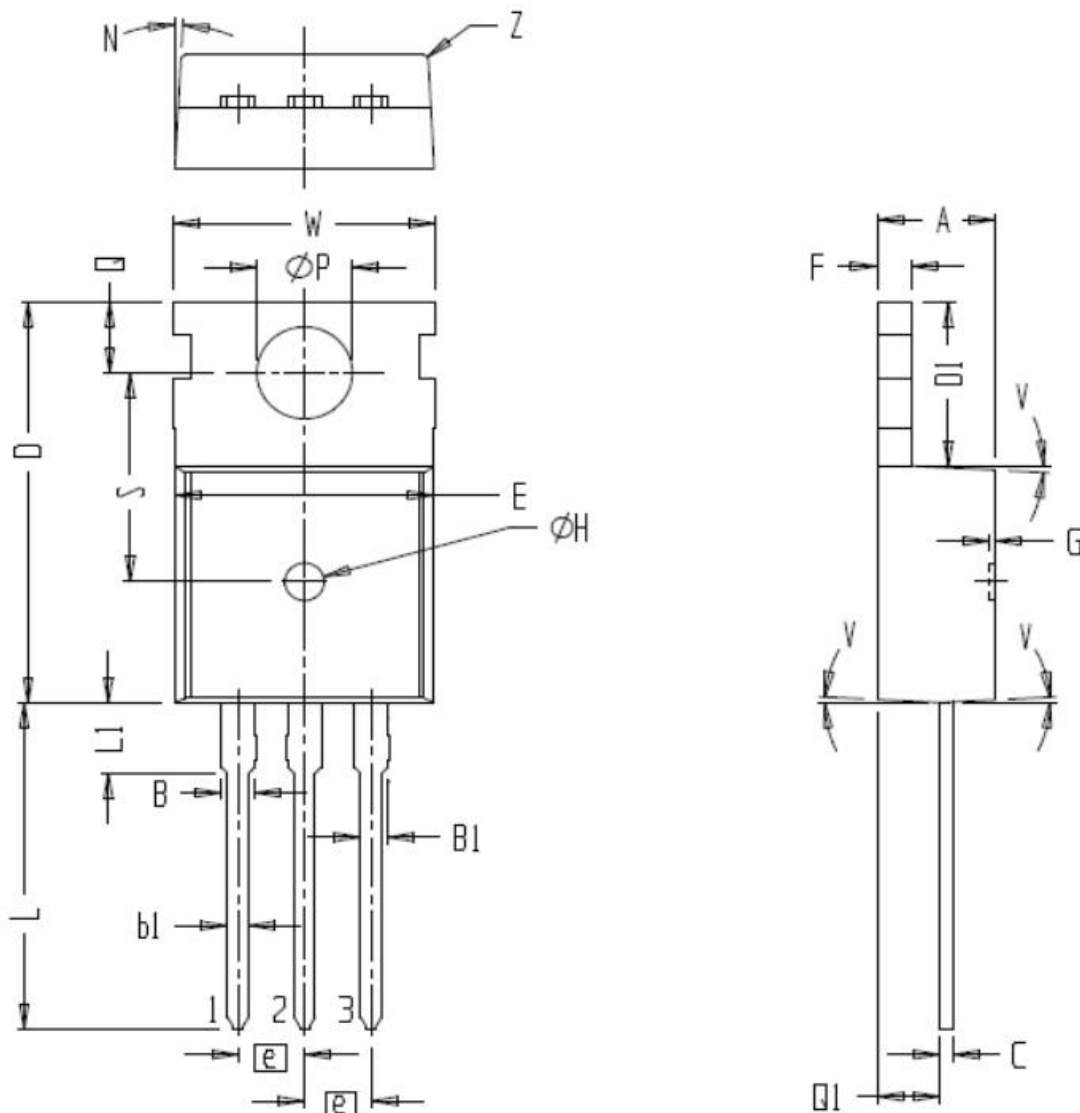
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## TO-220C Package Dimensions

UNIT: mm

SYMBOL	min	nom	max	SYMBOL	min	nom	max
A	4.00	4.40	4.80	E	9.40	9.90	10.40
B	1.17	1.32	1.47	e		2.54	
B1	0.91	1.06	1.21	F	1.15	1.30	1.45
b1	0.65	0.80	0.95	L	12.00	13.00	14.00
c	0.40	0.50	0.60	L1	2.50	3.00	3.50
D	14.90	15.90	16.90	Q	2.30	2.80	3.30
D1	6.10	6.60	7.10	Q1	1.90	2.40	2.90
W	9.50	10.00	10.50	$\phi P$	3.40	3.65	3.90
S		8.30		Z	0		0.20
$\phi H$		1.50		N		3 °	
G		0.10		V		3 °	





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### 注意事项:

- 1、在电路设计时请不要超过器件的最大额定值，否则会影响整机的可靠性。
- 2、MOSFET产品为静电敏感型器件，使用时应注意采取防静电保护措施，如佩戴防静电手环、设备接地等。
- 3、如需安装散热片，请注意控制扭力大小及散热片的平整度。
- 4、该规格书由华科公司制作，并可能不定期更改，恕不另行通知。
- 5、如有疑问，请及时联系我司销售代表。

### 版本履历表:

序号	版本号	修改时间	修改记录
1	V1.0	2022-9-2	首次发行